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PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

here application of

Docket No: Q63945

Hiroki KOIKE

Appln. No.: 09/824,751

Group Art Unit: 2818

Confirmation No.: 9722

Examiner: Unknown

Filed: April 4, 2001

For: SEMICONDUCTOR MEMORY DEVICE AND TESTING SYSTEM AND TESTING METHOD

INFORMATION DISCLOSURE STATEMENT  
UNDER 37 C.F.R. §§ 1.97 and 1.98

RECEIVED

NOV 03 2003

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Technology Center 2100

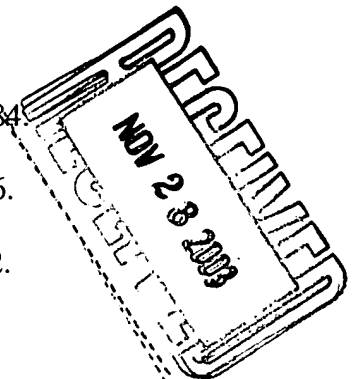
Sir:

In accordance with the duty of disclosure under 37 C.F.R. § 1.56, Applicant hereby notifies the U.S. Patent and Trademark Office of the documents which are listed on the attached PTO/SB/08 A & B (modified) form and/or listed herein and which the Examiner may deem material to patentability of the claims of the above-identified application.

One copy of each of the listed documents is submitted herewith.

1. Japanese Patent No. 59-198594, published November 10, 1984.
2. Japanese Patent No. 8-313594, published November 29, 1996.
3. Japanese Patent No. 57-200993, published December 9, 1982.
4. Japanese Patent No. 2001-148200, published May 29, 2001.

The present Information Disclosure Statement is being filed: (1) No later than three months from the application's filing date; (2) Before the mailing date of the first Office Action on the merits (whichever is later); or (3) Before the mailing date of the first Office Action after



INFORMATION DISCLOSURE STATEMENT

U.S. Appln. No.: 09/824,751

filing a request for continued examination (RCE) under §1.114, and therefore, no Statement under 37 C.F.R. § 1.97(e) or fee under 37 C.F.R. § 1.17(p) is required.

In compliance with the concise explanation requirement under 37 C.F.R. § 1.98(a)(3) for foreign language documents, Applicant encloses herewith a copy of a corresponding Japanese Office Action dated September 2, 2003, and an English translation of the pertinent portions thereof, which cites such documents and indicates the degree of relevance found by the foreign patent office.

The submission of the listed documents is not intended as an admission that any such document constitutes prior art against the claims of the present application. Applicant does not waive any right to take any action that would be appropriate to antedate or otherwise remove any listed document as a competent reference against the claims of the present application.

The USPTO is directed and authorized to charge all required fees, except for the Issue Fee and the Publication Fee, to Deposit Account No. 19-4880. Please also credit any overpayments to said Deposit Account. A duplicate copy of this paper is attached.

Respectfully submitted,  


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WASHINGTON OFFICE

23373

CUSTOMER NUMBER

Date: **OCT 30 2003**

## Reasons

The inventions as per the following claims of this application could have been easily invented, based on the inventions described in the publications indicated below which were distributed in Japan or abroad prior to the filing of this application, by a person having ordinary knowledge in the technical field of the invention prior to the filing of this application, and therefore cannot be patented, as per the stipulations of Article 29, Subsection 2 of the Patent Law.

## Details (For cited documents, see Table of cited documents)

- Claims: 1, 2 and 5
- Cited documents: 1
- Remarks

The device described in cited document 1 also comprises reference potential setting circuitry (node 148, FET 131, etc.) which sets an externally designated potential as the reference signal potential.

- Claims: 3
- Cited documents: 1 and 2
- Remarks:

As described in cited document 2, performing statistical processing and the like in a test device does not go beyond the conventional practice.

It is found that performing statistical processing, etc. in a test device to arrive at the constitution of the invention of the present application in testing a semiconductor device of cited document 1 is something which could be easily accomplished by a person skilled in the art.

- Claims: 4
- Cited documents: 1-3
- Remarks:

Providing some of the testing functionality in semiconductor memory is described in cited document 3.

B. The inventions as per the following claims of this application are identical to inventions first described in the specification or drawings appended to the patent applications indicated below, which are patent applications filed prior to but published in examined or unexamined form after the filing of this application; the inventor of this application is not the same as the person who made the aforementioned inventions as per the patent applications filed prior to the filing of this application, and the applicant of this application at the time of its filing was not the same as the applicants of the aforementioned patent applications, and therefore the inventions as per the following claims of this application cannot be patented, as per the stipulations of Article 29, Subsection 2 of the Patent Law.

Q63945

Details (For cited documents, see Table of cited documents)

- Claims: 6, 7, 10
- Cited documents: 4
- Remarks:

The invention described in application 4 performs AD conversion of data line potential. An AD conversion circuit conventionally has a sample holding circuit in the input section.

Therefore, it is found that application 4 describes an invention which does not differ from the invention of the present application.

- Claims: 9
- Cited documents: 4
- Remarks:

The invention described in application 4 comprises some testing functions.

No reasons for rejection have been discovered as of now for inventions as per claims other than the claims indicated in this notice of reasons for rejection. If any reasons for rejection are newly discovered, a notice of reasons for rejection will be issued.

Table of cited documents

1. Unexamined Patent Application Publication S59-198594 Gazette
2. Unexamined Patent Application Publication H08-313594 Gazette
3. Unexamined Patent Application Publication S57-200993 Gazette
4. Patent Application H11-331244 (Unexamined Patent Application Publication 2001-148200)